Temperature dependence of spin-dependent tunneling resistances of MgO-buffered Co₂MnSi/MgO/Co₂MnSi magnetic tunnel junctions

Yusuke Honda, Hong-xi Liu, Ken-ichi Matsuda, Tetsuya Uemura, and Masafumi Yamamoto

Division of Electronics for Informatics, Hokkaido University, Sapporo 060-0814, Japan Phone: +81-11-706-6442, E-mail: honda@nsed.ist.hokudai.ac.jp

1. Introduction

A heterostructure consisting of a potentially half-metallic Heusler alloy electrode 1) and a MgO barrier is highly advantageous as a spin source for magnetic junctions and for spin injection semiconductors. This because heterostructucture benefits not only from the high spin polarizations due to the half-metallic nature but also from the contribution of coherent tunneling of electrons in specific Bloch states to the enhancement of the tunneling spin polarization.²⁾ Co₂MnSi is one of the most investigated ferromagnetic electrode considerably materials amongst Co-based Heusler alloys. This is because of its theoretically predicted half-metallic nature¹⁾ and because of its high Curie temperature of 985 K. Furthermore, it has been theoretically predicted that coherent tunneling through the Δ_1 band of Co₂MnSi is dominant in an MTJ with Co₂MnSi electrodes and a MgO barrier.3)

We have recently investigated the effect of defects possibly associated with nonstoichiometry in Co₂MnSi thin films on spin-dependent tunneling characteristics have found that fully epitaxial Co₂MnSi/MgO/Co₂MnSi MTJs (CMS MTJs) with Mn-rich Co₂MnSi electrodes grown on a MgO-buffered substrate exhibited high MgO(001)magnetoresistance (TMR) ratios of 1135% at 4.2 K and 236% at 290 K, exceeding those of MTJs with Co2MnSi having an almost stoichiometric composition.⁴⁾ The observed higher TMR ratio for MTJs with Mn-rich Co₂MnSi electrodes was explained by suppressed Co_{Mn} antisites,⁵⁾ which caused a reduced density of minority-spin in-gap states around the Fermi level $(E_{\rm F})$. Our purpose of the present study was to clarify how the half-metallicity was influenced by Mn composition α in Co₂Mn_{\alpha}Si electrodes through investigating the temperature (T) dependence of the spin-dependent tunneling resistances for the parallel (P) and antiparallel (AP) magnetization configurations, R_P and $R_{\rm AP}$, of MgO-buffered CMS MTJs with various Mn compositions in CMS electrodes. We found that the T dependence of R_P showed characteristic behaviors strongly related to the change in the spin-dependent electronic structure with Mn composition α , although the T dependence of R_{AP} determined the overall Tdependence of the TMR ratio.

2. Experimental methods

The preparation of fully epitaxial CMS MTJs on MgO-buffered MgO(001) substrates with various values

of α has been reported in Ref. 4. Briefly, the fabricated MTJ layer structure was as follows: (from the substrate side) MgO buffer (10 nm)/CMS lower electrode (30 nm)/MgO barrier (2.0-3.0 nm)/CMS upper electrode (3-5 nm)/Ru (0.8 nm)/Co₉₀Fe₁₀ (2 nm)/IrMn (10 nm)/Ru cap (5 nm), grown on a MgO(001) single-crystal substrate. Each layer was successively deposited in an ultrahigh vacuum chamber (base pressure of $\sim 6 \times 10^{-8}$ The CMS electrodes were deposited by co-sputtering from a nearly stoichiometric CMS target and a Mn target to systematically vary the Mn composition in CMS. The film compositions of the CMS electrodes were determined to be $Co_2Mn_aSi_y$ ($\gamma = 1.0 \pm$ 0.06) by inductively coupled plasma optical emission spectroscopy with an accuracy of 2% for Co or Mn and 5% for Si. Hereafter, we denote $Co_2Mn_aSi_y$ ($y = 1.0 \pm$ 0.06) by Co₂Mn_aSi using the mean value of 1.0 for Si composition γ . The tunneling resistances R_P and R_{AP} were measured by a dc four-probe method at temperatures from 4.2 K to 290 K. The TMR ratio is defined as TMR $=(R_{AP}-R_P)/R_P.$

3. Experimental results and discussion

Figure 1 plots the T dependence of the TMR ratios of three CMS MTJs with various α values ranging from Mn-deficient $\alpha = 0.79$ to Mn-rich $\alpha = 1.29$: MTJ-1 with α = 0.79, MTJ-2 with α = 1.0, and MTJ-3 with α = 1.29. The TMR ratios at both 4.2 K and 290 K increased with increasing α from 355% at 4.2 K (97% at 290 K) for α = 0.79 to 1035% at 4.2 K (200% at 290 K) for $\alpha = 1.29$. Note that the normalized TMR ratios (the TMR ratio was normalized by its value at 290 K) of CMS MTJs with a higher TMR ratio at 4.2 K showed stronger T dependence (not shown), i.e., the relative decrease in the TMR ratio with increasing T up to 290 K is larger for CMS MTJs with a higher TMR ratio at 4.2 K. Figures 2 and 3 show the T dependence of the normalized R_{AP} (R_{AP} was normalized by its value at 290 K) and the normalized R_P (R_P was normalized by its value at 4.2 K) of these three MTJs. In contrast to very small relative changes in R_P with increasing T for all these MTJs (up to 6% change in the T range from 4.2 K to 290 K for MTJ-1 and almost within 1% for MTJ-2 and MTJ-3), the R_{AP} decreased significantly with increasing T: its relative change was two orders of magnitude larger than that of $R_{\rm P}$. Because of the considerably stronger T dependence of R_{AP} than that of R_P , the T dependence of the normalized TMR ratio was almost determined by that of R_{AP} (the normalized T dependence of the TMR ratio of each MTJ was in good agreement with that of the respective normalized $R_{\rm AP}$ (not shown)). Interestingly, the T dependence of the normalized $R_{\rm P}$ of MTJ-2 (α = 1.0) and MTJ-3 (α = 1.29) featuring higher TMR ratios at 4.2 K and 290 K showed qualitatively different behavior compared with that of MTJ-1 (α = 0.79) featuring a lower TMR ratio. $R_{\rm P}$ of MTJ-1 was almost independent of T up to a characteristic temperature T_2 of about 100 K and decreased as T increased for $T > T_2$. On the other hand, $R_{\rm P}$ of MTJ-3 (MTJ-2) increased as T increased for the T range from T_1 of about 40 K (40 K) to T_2 of about 190 K (180 K).

The decrease in R_P as T increased for $T > T_2$ for MTJ-1 can be explained by a model by Zhang $et \ al.^{6}$ in which magnon assisted tunneling is introduced under the assumption of T independent spin polarization (model-1). On the other hand, a model proposed by Shang $et \ al.^{7}$ in which the spin polarization decreases as T increases via thermal excitation of spin waves at finite temperatures (model-2) cannot explain the decrease in R_P as T increased.

The clear increase in R_P of MTJ-3 and MTJ-2 for $T_1 <$ $T < T_2$ can be ascribed to the decrease in the spin polarization arising from thermal spin fluctuations. 7,8) This means the influence of the decrease in the spin polarization arising from thermal spin fluctuation became dominant for determining the T dependence of $R_{\rm P}$ compared with the influence of the Zhang's mechanism⁶⁾ which increases not only the tunneling conductance for the antiparallel configuration but also that for the parallel configuration. The increase in R_P of MTJ-3 and MTJ-2 for $T_1 < T < T_2$ also indicates the decrease in the residual minority-spin in-gap states around $E_{\rm F}$, resulting in the decreased contribution to the enhancement of tunneling conductance from the Zhang's mechanism. This picture that MTJ-3 ($\alpha = 1.29$) and MTJ-2 ($\alpha = 1.0$) features the decreased minority-spin in-gap states at $E_{\rm F}$ compared with MTJ-1 ($\alpha = 0.79$) is consistent with the understanding that the higher TMR ratio observed for CMS MTJs with Mn-rich CMS electrodes can be attributed to suppressed minority-spin in-gap states around E_F for Mn-rich Co₂MnSi electrodes.⁵⁾

4. Conclusion

found that fully epitaxial In summary, we Co₂MnSi/MgO/Co₂MnSi MTJs MgO-buffered on MgO(001) substrates with Mn-rich Co₂MnSi electrodes and resulting high TMR ratios showed characteristic T dependence of the tunneling resistance for the parallel magnetization configuration which can be ascribed to reduced minority-spin in-gap states. Our finding suggest the importance of the T dependence of R_P to understand the key of the spin-dependent tunneling mechanism in MTJs with electrodes having high spin polarizations and the spin-dependent electronic structures.

References

- 1. S. Ishida et al., J. Phys. Soc. Japan 64 (1995) 2152.
- 2. W. H. Butler et al., Phys. Rev. B 63 (2001) 054416.
- 3. Y. Miura *et al.*, J. Phys.: Condens. Matter **19** (2007) 365228.

- 4. T. Ishikawa *et al.*, Appl. Phys. Lett. **95** (2009) 232512.
- M. Yamamoto *et al.*, J. Phys: Condens. Matter. 22 (2010) 164212.
- 6. S. Zhang et al., Phys. Rev. Lett. **79** (1997) 19.
- 7. C. H. Shang et al., Phys. Rev. B 58 (1998) R2917.
- 8. Y. Miura et al., Phys. Rev. B 83 (2011) 214411.

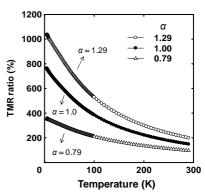


FIG. 1. Temperature dependence of the TMR ratios of $\text{Co}_2\text{Mn}_\alpha\text{Si/MgO/Co}_2\text{Mn}_\alpha\text{Si}$ MTJs (CMS MTJs) on MgO-buffered MgO(001) substrates with $\alpha=0.79$ (MTJ-1), 1.0 (MTJ-2), and 1.29 (MTJ-3) in $\text{Co}_2\text{Mn}_\alpha\text{Si}$ electrodes.

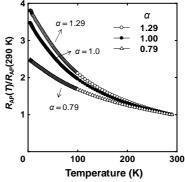


FIG. 2. Normalized T dependence of $R_{\rm AP}$ ($R_{\rm AP}$ was normalized by its value at 290 K) of CMS MTJs with α =0.79 (MTJ-1), 1.0 (MTJ-2), and 1.29 (MTJ-3) in Co₂Mn_{α}Si electrodes.

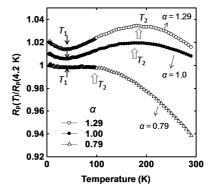


FIG. 3. Normalized T dependence of R_P (R_P was normalized by its value at 4.2 K) of CMS MTJs with $\alpha = 0.79$ (MTJ-1), 1.0 (MTJ-2), and 1.29 (MTJ-3). The second and third curves from the bottom have respective offsets of 0.01 and 0.02.